AMD Xilinx - XC6SLX9-N3FT256C Datasheet

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The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details	
Product Status	Obsolete
Number of LABs/CLBs	715
Number of Logic Elements/Cells	9152
Total RAM Bits	589824
Number of I/O	186
Number of Gates	-
Voltage - Supply	1.14V ~ 1.26V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 85°C (TJ)
Package / Case	256-LBGA
Supplier Device Package	256-FTBGA (17x17)
Purchase URL	https://www.e-xfl.com/product-detail/xilinx/xc6slx9-n3ft256c

SelectIO™ Interface DC Input and Output Levels

Table 7: **Recommended Operating Conditions for User I/Os Using Single-Ended Standards**

I/O Standard	V_{CCO} for Drivers[1]			V_{REF} for Inputs		
	V, Min	V, Nom	V, Max	V, Min	V, Nom	V, Max
LVTTL	3.0	3.3	3.45	V_{REF} is not used for these I/O standards		
LVCMOS33	3.0	3.3	3.45			
LVCMOS25	2.3	2.5	2.7			
LVCMOS18	1.65	1.8	1.95			
LVCMOS18_JEDEC	1.65	1.8	1.95			
LVCMOS15	1.4	1.5	1.6			
LVCMOS15_JEDEC	1.4	1.5	1.6			
LVCMOS12	1.1	1.2	1.3			
LVCMOS12_JEDEC	1.1	1.2	1.3			
PCI33_3[2]	3.0	3.3	3.45			
PCI66_3[2]	3.0	3.3	3.45			
I2C	2.7	3.0	3.45			
SMBUS	2.7	3.0	3.45			
SDIO	3.0	3.3	3.45			
MOBILE_DDR	1.7	1.8	1.9			
HSTL_I	1.4	1.5	1.6	0.68	0.75	0.9
HSTL_II	1.4	1.5	1.6	0.68	0.75	0.9
HSTL_III	1.4	1.5	1.6	–	0.9	–
HSTL_I_18	1.7	1.8	1.9	0.8	0.9	1.1
HSTL_II_18	1.7	1.8	1.9	–	0.9	–
HSTL_III_18	1.7	1.8	1.9	–	1.1	–
SSTL3_I	3.0	3.3	3.45	1.3	1.5	1.7
SSTL3_II	3.0	3.3	3.45	1.3	1.5	1.7
SSTL2_I	2.3	2.5	2.7	1.13	1.25	1.38
SSTL2_II	2.3	2.5	2.7	1.13	1.25	1.38
SSTL18_I	1.7	1.8	1.9	0.833	0.9	0.969
SSTL18_II	1.7	1.8	1.9	0.833	0.9	0.969
SSTL15_II	1.425	1.5	1.575	0.69	0.75	0.81

Notes:

1. V_{CCO} range required when using I/O standard for an output. Also required for MOBILE_DDR, PCI33_3, LVCMOS18_JEDEC, LVCMOS15_JEDEC, and LVCMOS12_JEDEC inputs, and for LVCMOS25 inputs when V_{CCAUX} = 3.3V.
2. For PCI systems, the transmitter and receiver should have common supplies for V_{CCO}.

Table 14: **GTP Transceiver Current Supply (per Lane)**

Symbol	Description	Typ[1]	Max	Units
$I_{MGTAVCC}$	GTP transceiver internal analog supply current	40.4	Note 2	mA
$I_{MGTAVTTTX}$	GTP transmitter termination supply current	27.4		mA
$I_{MGTAVTTRX}$	GTP receiver termination supply current	13.6		mA
$I_{MGTAVCCPLL}$	GTP transmitter and receiver PLL supply current	28.7		mA
$R_{MGTRREF}$	Precision reference resistor for internal calibration termination	50.0 ± 1% tolerance		Ω

Notes:
1. Typical values are specified at nominal voltage, 25°C, with a 2.5 Gb/s line rate, with a shared PLL use mode.
2. Values for currents of other transceiver configurations and conditions can be obtained by using the XPOWER Estimator (XPE) or XPOWER Analyzer (XPA) tools.

Table 15: **GTP Transceiver Quiescent Supply Current (per Lane)[1][2][3][4]**

Symbol	Description	Typ[5]	Max	Units
$I_{MGTAVCCQ}$	Quiescent MGTAVCC supply current	1.7	Note 2	mA
$I_{MGTAVTTTXQ}$	Quiescent MGTAVTTTX supply current	0.1		mA
$I_{MGTAVTTRXQ}$	Quiescent MGTAVTTRX supply current	1.2		mA
$I_{MGTAVCCPLLQ}$	Quiescent MGTAVCCPLL supply current	1.0		mA

Notes:
1. Device powered and unconfigured.
2. Currents for conditions other than values specified in this table can be obtained by using the XPOWER Estimator (XPE) or XPOWER Analyzer (XPA) tools.
3. GTP transceiver quiescent supply current for an entire device can be calculated by multiplying the values in this table by the number of available GTP transceivers.
4. Does not include power-up MGTAVTTRCAL supply current during device configuration.
5. Typical values are specified at nominal voltage, 25°C.

Table 17: **GTP Transceiver Clock DC Input Level Specification**

Symbol	DC Parameter	Min	Typ	Max	Units
V_{IDIFF}	Differential peak-to-peak input voltage	200	800	2000	mV
R_{IN}	Differential input resistance	80	100	120	Ω
C_{EXT}	Required external AC coupling capacitor	–	100	–	nF

GTP Transceiver Switching Characteristics

Consult UG386: *Spartan-6 FPGA GTP Transceivers User Guide* for further information.

Table 18: **GTP Transceiver Performance**

Symbol	Description	Speed Grade				Units
		-3	-3N	-2	-1L	
F_{GTPMAX}	Maximum GTP transceiver data rate	3.2	3.2	2.7	N/A	Gb/s
$F_{GTPRANGE1}$	GTP transceiver data rate range when PLL_TXDIVSEL_OUT = 1	1.88 to 3.2	1.88 to 3.2	1.88 to 2.7	N/A	Gb/s
$F_{GTPRANGE2}$	GTP transceiver data rate range when PLL_TXDIVSEL_OUT = 2	0.94 to 1.62	0.94 to 1.62	0.94 to 1.62	N/A	Gb/s
$F_{GTPRANGE3}$	GTP transceiver data rate range when PLL_TXDIVSEL_OUT = 4	0.6 to 0.81	0.6 to 0.81	0.6 to 0.81	N/A	Gb/s
$F_{GPLLMAX}$	Maximum PLL frequency	1.62	1.62	1.62	N/A	GHz
$F_{GPLLMIN}$	Minimum PLL frequency	0.94	0.94	0.94	N/A	GHz

Table 19: **GTP Transceiver Dynamic Reconfiguration Port (DRP) Switching Characteristics**

Symbol	Description	Speed Grade				Units
		-3	-3N	-2	-1L	
$F_{GTPDRPCLK}$	GTP transceiver DCLK (DRP clock) maximum frequency	125	125	100	N/A	MHz

Table 20: **GTP Transceiver Reference Clock Switching Characteristics**

Symbol	Description	Conditions	All LXT Speed Grades			Units
			Min	Typ	Max	
F_{GCLK}	Reference clock frequency range		60	–	160	MHz
T_{RCLK}	Reference clock rise time	20% – 80%	–	200	–	ps
T_{FCLK}	Reference clock fall time	80% – 20%	–	200	–	ps
T_{DCREF}	Reference clock duty cycle	Transceiver PLL only	45	50	55	%
T_{LOCK}	Clock recovery frequency acquisition time	Initial PLL lock	–	–	1	ms
T_{PHASE}	Clock recovery phase acquisition time	Lock to data after PLL has locked to the reference clock	–	–	200	µs

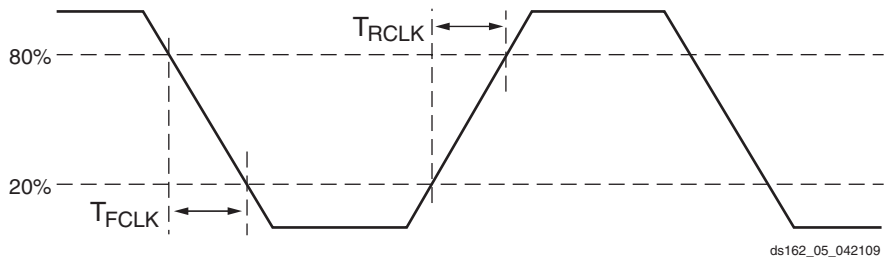

Figure 3: **Reference Clock Timing Parameters**

Table 28: **IOB Switching Characteristics for the Commercial (XC) Spartan-6 Devices *(Cont'd)***

I/O Standard	T_{IOPI}				T_{IOOP}				T_{IOTP}				Units
	Speed Grade				Speed Grade				Speed Grade				
	-3	-3N	-2	-1L[1]	-3	-3N	-2	-1L[1]	-3	-3N	-2	-1L[1]	
LVCMOS18, Slow, 24 mA	1.18	1.30	1.43	2.04	1.99	2.13	2.33	2.95	1.99	2.13	2.33	2.95	ns
LVCMOS18, Fast, 2 mA	1.18	1.30	1.43	2.04	3.59	3.73	3.93	4.53	3.59	3.73	3.93	4.53	ns
LVCMOS18, Fast, 4 mA	1.18	1.30	1.43	2.04	2.39	2.53	2.73	3.35	2.39	2.53	2.73	3.35	ns
LVCMOS18, Fast, 6 mA	1.18	1.30	1.43	2.04	1.88	2.02	2.22	2.84	1.88	2.02	2.22	2.84	ns
LVCMOS18, Fast, 8 mA	1.18	1.30	1.43	2.04	1.81	1.95	2.15	2.77	1.81	1.95	2.15	2.77	ns
LVCMOS18, Fast, 12 mA	1.18	1.30	1.43	2.04	1.71	1.85	2.05	2.67	1.71	1.85	2.05	2.67	ns
LVCMOS18, Fast, 16 mA	1.18	1.30	1.43	2.04	1.71	1.85	2.05	2.67	1.71	1.85	2.05	2.67	ns
LVCMOS18, Fast, 24 mA	1.18	1.30	1.43	2.04	1.71	1.85	2.05	2.67	1.71	1.85	2.05	2.67	ns
LVCMOS18_JEDEC, QUIETIO, 2 mA	0.94	1.06	1.19	1.41	5.91	6.05	6.25	6.79	5.91	6.05	6.25	6.79	ns
LVCMOS18_JEDEC, QUIETIO, 4 mA	0.94	1.06	1.19	1.41	4.75	4.89	5.09	5.64	4.75	4.89	5.09	5.64	ns
LVCMOS18_JEDEC, QUIETIO, 6 mA	0.94	1.06	1.19	1.41	4.04	4.18	4.38	4.96	4.04	4.18	4.38	4.96	ns
LVCMOS18_JEDEC, QUIETIO, 8 mA	0.94	1.06	1.19	1.41	3.71	3.85	4.05	4.62	3.71	3.85	4.05	4.62	ns
LVCMOS18_JEDEC, QUIETIO, 12 mA	0.94	1.06	1.19	1.41	3.35	3.49	3.69	4.28	3.35	3.49	3.69	4.28	ns
LVCMOS18_JEDEC, QUIETIO, 16 mA	0.94	1.06	1.19	1.41	3.20	3.34	3.54	4.13	3.20	3.34	3.54	4.13	ns
LVCMOS18_JEDEC, QUIETIO, 24 mA	0.94	1.06	1.19	1.41	2.96	3.10	3.30	3.98	2.96	3.10	3.30	3.98	ns
LVCMOS18_JEDEC, Slow, 2 mA	0.94	1.06	1.19	1.41	4.59	4.73	4.93	5.54	4.59	4.73	4.93	5.54	ns
LVCMOS18_JEDEC, Slow, 4 mA	0.94	1.06	1.19	1.41	3.69	3.83	4.03	4.60	3.69	3.83	4.03	4.60	ns
LVCMOS18_JEDEC, Slow, 6 mA	0.94	1.06	1.19	1.41	3.00	3.14	3.34	3.94	3.00	3.14	3.34	3.94	ns
LVCMOS18_JEDEC, Slow, 8 mA	0.94	1.06	1.19	1.41	2.19	2.33	2.53	3.18	2.19	2.33	2.53	3.18	ns
LVCMOS18_JEDEC, Slow, 12 mA	0.94	1.06	1.19	1.41	1.99	2.13	2.33	2.95	1.99	2.13	2.33	2.95	ns
LVCMOS18_JEDEC, Slow, 16 mA	0.94	1.06	1.19	1.41	1.99	2.13	2.33	2.95	1.99	2.13	2.33	2.95	ns
LVCMOS18_JEDEC, Slow, 24 mA	0.94	1.06	1.19	1.41	1.99	2.13	2.33	2.95	1.99	2.13	2.33	2.95	ns
LVCMOS18_JEDEC, Fast, 2 mA	0.94	1.06	1.19	1.41	3.57	3.71	3.91	4.52	3.57	3.71	3.91	4.52	ns
LVCMOS18_JEDEC, Fast, 4 mA	0.94	1.06	1.19	1.41	2.39	2.53	2.73	3.35	2.39	2.53	2.73	3.35	ns
LVCMOS18_JEDEC, Fast, 6 mA	0.94	1.06	1.19	1.41	1.88	2.02	2.22	2.84	1.88	2.02	2.22	2.84	ns
LVCMOS18_JEDEC, Fast, 8 mA	0.94	1.06	1.19	1.41	1.80	1.94	2.14	2.76	1.80	1.94	2.14	2.76	ns
LVCMOS18_JEDEC, Fast, 12 mA	0.94	1.06	1.19	1.41	1.72	1.86	2.06	2.68	1.72	1.86	2.06	2.68	ns
LVCMOS18_JEDEC, Fast, 16 mA	0.94	1.06	1.19	1.41	1.72	1.86	2.06	2.68	1.72	1.86	2.06	2.68	ns
LVCMOS18_JEDEC, Fast, 24 mA	0.94	1.06	1.19	1.41	1.72	1.86	2.06	2.68	1.72	1.86	2.06	2.68	ns
LVCMOS15, QUIETIO, 2 mA	0.98	1.10	1.23	1.79	5.47	5.61	5.81	6.38	5.47	5.61	5.81	6.38	ns
LVCMOS15, QUIETIO, 4 mA	0.98	1.10	1.23	1.79	4.61	4.75	4.95	5.51	4.61	4.75	4.95	5.51	ns
LVCMOS15, QUIETIO, 6 mA	0.98	1.10	1.23	1.79	4.07	4.21	4.41	4.97	4.07	4.21	4.41	4.97	ns
LVCMOS15, QUIETIO, 8 mA	0.98	1.10	1.23	1.79	3.91	4.05	4.25	4.81	3.91	4.05	4.25	4.81	ns
LVCMOS15, QUIETIO, 12 mA	0.98	1.10	1.23	1.79	3.53	3.67	3.87	4.51	3.53	3.67	3.87	4.51	ns
LVCMOS15, QUIETIO, 16 mA	0.98	1.10	1.23	1.79	3.32	3.46	3.66	4.31	3.32	3.46	3.66	4.31	ns
LVCMOS15, Slow, 2 mA	0.98	1.10	1.23	1.79	4.18	4.32	4.52	5.11	4.18	4.32	4.52	5.11	ns
LVCMOS15, Slow, 4 mA	0.98	1.10	1.23	1.79	3.42	3.56	3.76	4.34	3.42	3.56	3.76	4.34	ns
LVCMOS15, Slow, 6 mA	0.98	1.10	1.23	1.79	2.29	2.43	2.63	3.24	2.29	2.43	2.63	3.24	ns

Table 29: **IOB Switching Characteristics for the Automotive XA Spartan-6 and the Spartan-6Q Devices[1] *(Cont'd)***

I/O Standard	T_{IOPI}		T_{IOOP}		T_{IOTP}		Units
	Speed Grade		Speed Grade		Speed Grade		
	-3	-2	-3	-2	-3	-2	
LVCMOS12, QUIETIO, 6 mA	0.98	1.16	4.79	4.99	4.79	4.99	ns
LVCMOS12, QUIETIO, 8 mA	0.98	1.16	4.43	4.63	4.43	4.63	ns
LVCMOS12, QUIETIO, 12 mA	0.98	1.16	4.18	4.38	4.18	4.38	ns
LVCMOS12, Slow, 2 mA	0.98	1.16	5.12	5.32	5.12	5.32	ns
LVCMOS12, Slow, 4 mA	0.98	1.16	3.00	3.20	3.00	3.20	ns
LVCMOS12, Slow, 6 mA	0.98	1.16	2.91	3.11	2.91	3.11	ns
LVCMOS12, Slow, 8 mA	0.98	1.16	2.51	2.71	2.51	2.71	ns
LVCMOS12, Slow, 12 mA	0.98	1.16	2.25	2.45	2.25	2.45	ns
LVCMOS12, Fast, 2 mA	0.98	1.16	3.60	3.80	3.60	3.80	ns
LVCMOS12, Fast, 4 mA	0.98	1.16	2.49	2.69	2.49	2.69	ns
LVCMOS12, Fast, 6 mA	0.98	1.16	1.94	2.14	1.94	2.14	ns
LVCMOS12, Fast, 8 mA	0.98	1.16	1.82	2.02	1.82	2.02	ns
LVCMOS12, Fast, 12 mA	0.98	1.16	1.80	2.00	1.80	2.00	ns
LVCMOS12_JEDEC, QUIETIO, 2 mA	1.57	1.75	6.53	6.73	6.53	6.73	ns
LVCMOS12_JEDEC, QUIETIO, 4 mA	1.57	1.75	5.12	5.32	5.12	5.32	ns
LVCMOS12_JEDEC, QUIETIO, 6 mA	1.57	1.75	4.81	5.01	4.81	5.01	ns
LVCMOS12_JEDEC, QUIETIO, 8 mA	1.57	1.75	4.44	4.64	4.44	4.64	ns
LVCMOS12_JEDEC, QUIETIO, 12 mA	1.57	1.75	4.20	4.40	4.20	4.40	ns
LVCMOS12_JEDEC, Slow, 2 mA	1.57	1.75	5.14	5.34	5.14	5.34	ns
LVCMOS12_JEDEC, Slow, 4 mA	1.57	1.75	2.99	3.19	2.99	3.19	ns
LVCMOS12_JEDEC, Slow, 6 mA	1.57	1.75	2.90	3.10	2.90	3.10	ns
LVCMOS12_JEDEC, Slow, 8 mA	1.57	1.75	2.50	2.70	2.50	2.70	ns
LVCMOS12_JEDEC, Slow, 12 mA	1.57	1.75	2.26	2.46	2.26	2.46	ns
LVCMOS12_JEDEC, Fast, 2 mA	1.57	1.75	3.60	3.80	3.60	3.80	ns
LVCMOS12_JEDEC, Fast, 4 mA	1.57	1.75	2.49	2.69	2.49	2.69	ns
LVCMOS12_JEDEC, Fast, 6 mA	1.57	1.75	1.94	2.14	1.94	2.14	ns
LVCMOS12_JEDEC, Fast, 8 mA	1.57	1.75	1.83	2.03	1.83	2.03	ns
LVCMOS12_JEDEC, Fast, 12 mA	1.57	1.75	1.80	2.00	1.80	2.00	ns

Notes:

1. The Spartan-6Q FPGA -1L values are listed in Table 28.

Table 30 summarizes the value of T_{IOTPHZ}. T_{IOTPHZ} is described as the delay from the T pin to the IOB pad through the output buffer of an IOB pad, when 3-state is enabled (i.e., a high impedance state). These delays are measured using LVCMOS25, Fast, 12 mA.

Table 30: **IOB 3-state ON Output Switching Characteristics (T_{IOTPHZ})**

Symbol	Description	Speed Grade				Units
		-3	-3N	-2	-1L	
T_{IOTPHZ}	T input to Pad high-impedance	1.39	1.59	1.59	1.91	ns

Output Delay Measurements

Output delays are measured using a Tektronix P6245 TDS500/600 probe (< 1 pF) across approximately 4" of FR4 microstrip trace. Standard termination was used for all testing. The propagation delay of the 4" trace is characterized separately and subtracted from the final measurement, and is therefore not included in the generalized test setups shown in Figure 4 and Figure 5.

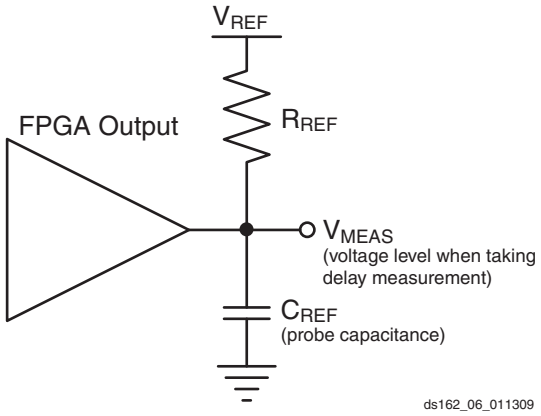

Figure 4: **Single-Ended Test Setup**

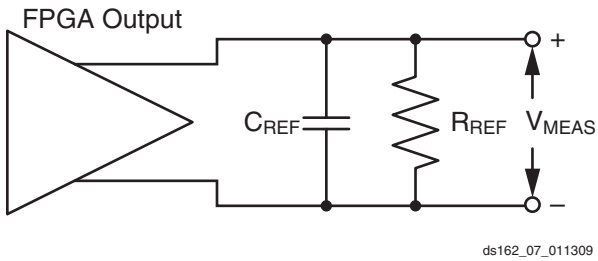

Figure 5: **Differential Test Setup**

Measurements and test conditions are reflected in the IBIS models except where the IBIS format precludes it. Parameters V_{REF}, R_{REF}, C_{REF}, and V_{MEAS} fully describe the test conditions for each I/O standard. The most accurate prediction of propagation delay in any given application can be obtained through IBIS simulation, using the following method:

1. Simulate the output driver of choice into the generalized test setup, using values from Table 32.
2. Record the time to V_{MEAS}.
3. Simulate the output driver of choice into the actual PCB trace and load, using the appropriate IBIS model or capacitance value to represent the load.
4. Record the time to V_{MEAS}.
5. Compare the results of steps 2 and 4. The increase or decrease in delay yields the actual propagation delay of the PCB trace.

Table 32: **Output Delay Measurement Methodology**

Description	I/O Standard Attribute	R_{REF} (Ω)	C_{REF} (1) (pF)	V_{MEAS} (V)	V_{REF} (V)
LVTTL (Low-Voltage Transistor-Transistor Logic)	LVTTL (all)	1M	0	1.4	0
LVCMOS (Low-Voltage CMOS), 3.3V	LVCMOS33	1M	0	1.65	0
LVCMOS, 2.5V	LVCMOS25	1M	0	1.25	0
LVCMOS, 1.8V	LVCMOS18	1M	0	0.9	0
LVCMOS, 1.5V	LVCMOS15	1M	0	0.75	0
LVCMOS, 1.2V	LVCMOS12	1M	0	0.6	0
PCI (Peripheral Component Interface) 33 MHz and 66 MHz, 3.3V	PCI33_3, PCI66_3 (rising edge)	25	10 (2)	0.94	0
	PCI33_3, PCI66_3 (falling edge)	25	10 (2)	2.03	3.3
HSTL (High-Speed Transceiver Logic), Class I	HSTL_I	50	0	V_{REF}	0.75
HSTL, Class II	HSTL_II	25	0	V_{REF}	0.75
HSTL, Class III	HSTL_III	50	0	0.9	1.5
HSTL, Class I, 1.8V	HSTL_I_18	50	0	V_{REF}	0.9
HSTL, Class II, 1.8V	HSTL_II_18	25	0	V_{REF}	0.9
HSTL, Class III, 1.8V	HSTL_III_18	50	0	1.1	1.8
SSTL (Stub Series Terminated Logic), Class I, 1.8V	SSTL18_I	50	0	V_{REF}	0.9
SSTL, Class II, 1.8V	SSTL18_II	25	0	V_{REF}	0.9
SSTL, Class I, 2.5V	SSTL2_I	50	0	V_{REF}	1.25

Table 32: **Output Delay Measurement Methodology *(Cont'd)***

Description	I/O Standard Attribute	R_{REF} (Ω)	C_{REF}[1] (pF)	V_{MEAS} (V)	V_{REF} (V)
SSTL, Class II, 2.5V	SSTL2_II	25	0	V_{REF}	1.25
SSTL, Class II, 1.5V	SSTL15_II	25	0	V_{REF}	0.75
LVDS (Low-Voltage Differential Signaling), 2.5V & 3.3V	LVDS_25, LVDS_33	100	0	0[3]	–
BLVDS (Bus LVDS), 2.5V	BLVDS_25	Note 4	0	0[3]	–
Mini-LVDS, 2.5V & 3.3V	MINI_LVDS_25, MINI_LVDS_33	100	0	0[3]	–
RSDS (Reduced Swing Differential Signaling), 2.5V & 3.3V	RSDS_25, RSDS_33	100	0	0[3]	–
TMDS (Transition Minimized Differential Signaling), 3.3V	TMDS_33	Note 5	0	0[3]	–
PPDS (Point-to-Point Differential Signaling, 2.5V & 3.3V	PPDS_25, PPDS_33	100	0	0[3]	–

Notes:
1. C_{REF} is the capacitance of the probe, nominally 0 pF.
2. Per PCI specifications.
3. The value given is the differential output voltage.
4. See the *BLVDS Output Termination* section in UG381, *Spartan-6 FPGA SelectIO Resources User Guide*.
5. See the *TMDS_33 Termination* section in UG381, *Spartan-6 FPGA SelectIO Resources User Guide*.

Simultaneously Switching Outputs

Due to package electrical parasitics, a given package supports a limited number of simultaneous switching outputs (SSOs) when using fast, high-drive outputs. Table 33 and Table 34 provide guidelines for the recommended maximum allowable number of SSOs. These guidelines describe the maximum number of user I/O pins of an output signal standard that should simultaneously switch in the same direction, while maintaining a safe level of switching noise for that particular signal standard. Meeting these guidelines for the stated test conditions ensures that the FPGA operates free from the adverse effects of GND and power bounce.

For each device/package combination, Table 33 provides the number of equivalent V_{CCO}/GND pairs per bank. For each output signal standard and drive strength, Table 34 recommends the maximum number of SSOs, switching in the same direction, allowed per V_{CCO}/GND pair within an I/O bank. The guidelines are categorized by package style, slew rate, and output drive current. The number of SSOs are also specified by I/O bank. Multiply the appropriate numbers from each table to calculate the maximum number of SSOs allowed within an I/O bank. The guidelines assume that all pins within a bank use the same I/O standard. Exceeding these SSO guidelines can result in increased power or GND bounce, degraded signal integrity, or increased system jitter. For a given I/O standard, if the SSO limit per pair in Table 34 is greater than the maximum I/O per pair in Table 33, then there is no SSO limit for the exclusive use of that I/O standard.

The recommended maximum SSO values assume that the FPGA is soldered on a printed circuit board and that the board uses sound design practices. Due to the additional inductance introduced by the socket, the SSO values do not apply for FPGAs mounted in sockets. The SSO values assume that the V_{CCAUX} is powered at 3.3V. Setting V_{CCAUX} to 2.5V provides better SSO characteristics. For more detail, see UG381: *Spartan-6 FPGA SelectIO Resources User Guide*.

Table 34: **SSO Limit per V_{CCO}/GND Pair *(Cont'd)***

V_{CCO}	I/O Standard	Drive	Slew	SSO Limit per V_{CCO}/GND Pair			
				All TQG144, CPG196, CSG225, FT(G)256, and LX devices in CSG324		All CS(G)484, FG(G)484, FG(G)676, FG(G)900, and LXT devices in CSG324	
				Bank 0/2	Bank 1/3	Bank 0/2	Bank 1/3/4/5
2.5V	LVCMOS25	2	Fast	38	43	38	43
			Slow	46	52	46	48
			QuietIO	57	64	57	59
		4	Fast	21	24	21	23
			Slow	26	31	26	27
			QuietIO	33	32	33	30
		6	Fast	15	17	15	16
			Slow	19	22	19	19
			QuietIO	25	23	25	19
		8	Fast	12	15	12	14
			Slow	15	18	15	16
			QuietIO	21	19	21	16
		12	Fast	1	3	1	1
			Slow	2	7	2	4
			QuietIO	3	8	3	8
		16	Fast	1	3	1	1
			Slow	3	7	3	3
			QuietIO	4	9	4	8
		24	Fast	N/A	3	N/A	1
			Slow	N/A	5	N/A	2
			QuietIO	N/A	8	N/A	6
	SSTL_2_I (3)			10	11	10	11
	SSTL_2_II (3)			N/A	7	N/A	7
	DIFF_SSTL_2_I (3)			30	33	30	33
	DIFF_SSTL_2_II (3)			N/A	21	N/A	24

Table 34: **SSO Limit per V_{CCO}/GND Pair *(Cont'd)***

V_{CCO}	I/O Standard	Drive	Slew	SSO Limit per V_{CCO}/GND Pair			
				All TQG144, CPG196, CSG225, FT(G)256, and LX devices in CSG324		All CS(G)484, FG(G)484, FG(G)676, FG(G)900, and LXT devices in CSG324	
				Bank 0/2	Bank 1/3	Bank 0/2	Bank 1/3/4/5
3.3V	LVCMOS33	2	Fast	42	46	42	44
			Slow	50	55	50	49
			QuietIO	60	68	60	60
		4	Fast	21	27	21	25
			Slow	32	37	32	32
			QuietIO	39	42	39	37
		6	Fast	14	19	14	17
			Slow	19	25	19	22
			QuietIO	29	30	29	25
		8	Fast	11	15	11	14
			Slow	15	20	15	18
			QuietIO	25	24	25	20
		12	Fast	1	3	1	1
			Slow	2	5	2	2
			QuietIO	4	9	4	7
		16	Fast	1	2	1	1
			Slow	1	5	1	1
			QuietIO	3	10	3	8
		24	Fast	1	2	1	1
			Slow	2	5	2	1
			QuietIO	7	9	7	7

Table 34: **SSO Limit per V_{CCO}/GND Pair *(Cont'd)***

V_{CCO}	I/O Standard	Drive	Slew	SSO Limit per V_{CCO}/GND Pair			
				All TQG144, CPG196, CSG225, FT(G)256, and LX devices in CSG324		All CS(G)484, FG(G)484, FG(G)676, FG(G)900, and LXT devices in CSG324	
				Bank 0/2	Bank 1/3	Bank 0/2	Bank 1/3/4/5
Various	LVDS_33			16	N/A	16	N/A
	LVDS_25			20	N/A	20	N/A
	BLVDS_25			20	48	20	20
	MINI_LVDS_33			13	N/A	13	N/A
	MINI_LVDS_25			18	N/A	18	N/A
	RSDS_33			12	N/A	12	N/A
	RSDS_25			15	N/A	15	N/A
	TMDS_33			83	N/A	83	N/A
	PPDS_33			12	N/A	12	N/A
	PPDS_25			16	N/A	16	N/A
	DISPLAY_PORT			42	40	42	30
	I2C			47	55	47	42
	SMBUS			44	52	44	40

Notes:

1. SSO limits greater than the number of I/O per V_{CCO}/GND pair (Table 33) indicate No Limit for the given I/O standard. They are provided in this table to calculate limits when using multiple I/O standards in a bank.
2. Not available (N/A) indicates that the I/O standard is not available in the given bank.
3. When used with the MCB, these signals are exempt from SSO analysis due to the known activity of the MCB switching patterns. SSO performance is validated for all MCB instances. MCB outputs can, in some cases, exceed the SSO limits.

Input/Output Logic Switching Characteristics

Table 35: **ILOGIC2 Switching Characteristics**

Symbol	Description	Speed Grade				Units
		-3	-3N	-2	-1L	
Setup/Hold						
T_{ICE0CK}/T_{ICKCE0}	CE0 pin Setup/Hold with respect to CLK	0.56/ –0.30	0.56/ –0.25	0.79/ –0.22	1.21/ –0.52	ns
T_{ISRCK}/T_{ICKSR}	SR pin Setup/Hold with respect to CLK	0.74/ –0.23	0.74/ –0.22	0.98/ –0.20	1.31/ –0.45	ns
T_{IDOCK}/T_{IOCKD}	D pin Setup/Hold with respect to CLK without Delay	1.19/ –0.83	1.36/ –0.83	1.73/ –0.83	2.18/ –1.77	ns
T_{IDOCKD}/T_{IOCKDD}	DDLY pin Setup/Hold with respect to CLK (using IODELAY2)	0.31/ 0.00	0.47/ 0.00	0.54/ 0.00	0.63/ –0.39	ns
Combinatorial						
T_{IDI}	D pin to O pin propagation delay, no Delay	0.95	1.28	1.53	2.25	ns
T_{IDID}	DDLY pin to O pin propagation delay (using IODELAY2)	0.23	0.39	0.44	0.74	ns
Sequential Delays						
T_{IDLO}	D pin to Q pin using flip-flop as a latch without Delay	1.56	1.86	2.39	3.49	ns
T_{IDLOD}	DDLY pin to Q1 pin using flip-flop as a latch (using IODELAY2)	0.68	0.97	1.20	1.94	ns
T_{ICKQ}	CLK to Q outputs for XC devices	1.03	1.24	1.43	2.11	ns
	CLK to Q outputs for XA and XQ devices	1.38	N/A	1.78	2.11	ns
$T_{RQ\_ILOGIC2}$	SR pin to Q outputs	1.81	1.81	2.50	3.05	ns

Table 36: **OLOGIC2 Switching Characteristics**

Symbol	Description	Speed Grade				Units
		-3	-3N	-2	-1L	
Setup/Hold						
T_{ODCK}/T_{OCKD}	D1/D2 pins Setup/Hold with respect to CLK	0.81/ –0.05	0.86/ –0.05	1.18/ 0.00	1.73/ –0.27	ns
T_{OOCECK}/T_{OCKOCE}	OCE pin Setup/Hold with respect to CLK	0.75/ –0.10	0.75/ –0.10	1.01/ –0.05	1.66/ –0.23	ns
T_{OSRCK}/T_{OCKSR}	SR pin Setup/Hold with respect to CLK	0.70/ –0.28	0.79/ –0.28	1.03/ –0.23	1.39/ –0.47	ns
T_{OTCK}/T_{OCKT}	T1/T2 pins Setup/Hold with respect to CLK	0.24/ –0.08	0.56/ –0.06	0.83/ –0.01	0.99/ –0.19	ns
T_{OTCECK}/T_{OCKTCE}	TCE pin Setup/Hold with respect to CLK	0.58/ –0.06	0.72/ –0.06	1.18/ –0.01	1.51/ –0.13	ns
Sequential Delays						
T_{OCKQ}	CLK to OQ/TQ out for XC devices	0.48	0.51	0.74	0.74	ns
	CLK to OQ/TQ out for XA and XQ devices	0.85	N/A	1.16	0.74	ns
$T_{RQ\_OLOGIC2}$	SR pin to OQ/TQ out	1.81	1.81	2.50	3.05	ns

CLB Switching Characteristics (SLICEM Only)

Table 40: **CLB Switching Characteristics (SLICEM Only)**

Symbol	Description	Speed Grade				Units
		-3	-3N	-2	-1L	
Combinatorial Delays						
T_{ILO}	An – Dn LUT inputs to A to D outputs	0.21	0.26	0.26	0.46	ns, Max
	An – Dn LUT inputs through F7AMUX/F7BMUX to AMUX/CMUX output	0.37	0.43	0.43	0.77	ns, Max
T_{OPAB}	An – Dn LUT inputs through F7AMUX or F7BMUX and F8MUX to BMUX output	0.37	0.46	0.46	0.84	ns, Max
T_{ITO}	An – Dn LUT inputs through latch to AQ – DQ outputs	0.82	0.95	0.95	1.64	ns, Max
T_{TITO_LOGIC}	An – Dn LUT inputs to AQ – DQ outputs (latch as logic)	0.82	0.95	0.95	1.64	ns, Max
T_{OPCYA}	An LUT inputs to COUT output	0.38	0.48	0.48	0.69	ns, Max
T_{OPCYB}	Bn LUT inputs to COUT output	0.38	0.49	0.49	0.71	ns, Max
T_{OPCYC}	Cn LUT inputs to COUT output	0.28	0.33	0.33	0.55	ns, Max
T_{OPCYD}	Dn LUT inputs to COUT output	0.28	0.35	0.35	0.52	ns, Max
T_{AXCY}	AX input to COUT output	0.21	0.26	0.26	0.36	ns, Max
T_{BXCY}	BX input to COUT output	0.13	0.16	0.16	0.18	ns, Max
T_{CXCY}	CX input to COUT output	0.10	0.12	0.12	0.09	ns, Max
T_{DXCY}	DX input to COUT output	0.09	0.11	0.11	0.09	ns, Max
T_{BYP}	CIN input to COUT output	0.08	0.10	0.10	0.06	ns, Max
T_{CINA}	CIN input to AMUX output	0.21	0.22	0.22	0.47	ns, Max
T_{CINB}	CIN input to BMUX output	0.30	0.31	0.31	0.57	ns, Max
T_{CINC}	CIN input to CMUX output	0.29	0.31	0.31	0.58	ns, Max
T_{CIND}	CIN input to DMUX output	0.31	0.32	0.32	0.68	ns, Max
Sequential Delays						
T_{CKO}	Clock to AQ – DQ outputs	0.45	0.53	0.53	0.74	ns, Max
Setup and Hold Times of CLB Flip-Flops Before/After Clock CLK						
T_{DICK}/T_{CKDI}	AX – DX input to CLK on A – D flip-flops	0.42/ 0.28	0.47/ 0.39	0.47/ 0.39	0.90/ 0.56	ns, Min
T_{CECK}/T_{CKCE}	CE input to CLK on A – D flip-flops	0.31/ –0.07	0.37/ –0.07	0.37/ –0.07	0.59/ –0.27	ns, Min
T_{SRCK}/T_{CKSR}	SR input to CLK on A – D flip-flops for XC devices	0.41/ 0.02	0.42/ 0.02	0.42/ 0.02	0.68/ –0.29	ns, Min
	SR input to CLK on A – D flip-flops for XA and XQ devices	0.41/ 0.02	N/A	0.44/ 0.02	0.68/ –0.29	ns, Min
T_{CINCK}/T_{CKCIN}	CIN input to CLK on A – D flip-flops	0.31/ –0.17	0.31/ –0.13	0.31/ –0.13	0.81/ –0.42	ns, Min
Set/Reset						
T_{RPW}	SR input minimum pulse width	0.41	0.48	0.48	1.37	ns, Min
T_{RQ}	Delay from SR input to AQ – DQ flip-flops	0.60	0.70	0.70	0.88	ns, Max
T_{CEO}	Delay from CE input to AQ – DQ flip-flops	0.60	0.65	0.65	0.90	ns, Max
F_{TOG}	Toggle frequency (for export control)	862	806	667	500	MHz

DSP48A1 Switching Characteristics

Table 44: **DSP48A1 Switching Characteristics**

Symbol	Description	Pre-adder	Multiplier	Post-adder	Speed Grade				Units
					-3	-3N	-2	-1L	
Setup and Hold Times of Data/Control Pins to the Input Register Clock									
$T_{DSPDCK\_A\_A1REG}$/ $T_{DSPCKD\_A\_A1REG}$	A input to A1 register CLK	N/A	N/A	N/A	0.15/ 0.09	0.17/ 0.09	0.17/ 0.09	0.32/ 0.09	ns
$T_{DSPDCK\_D\_B1REG}$/ $T_{DSPCKD\_D\_B1REG}$	D input to B1 register CLK	Yes	N/A	N/A	1.90/ –0.07	1.95/ –0.07	1.95/ –0.07	2.82/ –0.07	ns
$T_{DSPDCK\_C\_CREG}$/ $T_{DSPCKD\_C\_CREG}$	C input to C register CLK for XC devices	N/A	N/A	N/A	0.11/ 0.15	0.13/ 0.15	0.13/ 0.15	0.24/ 0.09	ns
	C input to C register CLK for XA and XQ devices				0.11/ 0.19	N/A	0.13/ 0.23	0.24/ 0.09	
$T_{DSPDCK\_D\_DREG}$/ $T_{DSPCKD\_D\_DREG}$	D input to D register CLK for XC devices	N/A	N/A	N/A	0.09/ 0.15	0.10/ 0.15	0.10/ 0.15	0.19/ 0.12	ns
	D input to D register CLK for XA and XQ devices				0.09/ 0.23	N/A	0.10/ 0.27	0.19/ 0.12	
$T_{DSPDCK\_OPMODE\_B1REG}$/ $T_{DSPCKD\_OPMODE\_B1REG}$	OPMODE input to B1 register CLK	Yes	N/A	N/A	1.97/ 0.01	2.00/ 0.01	2.00/ 0.01	2.85/ 0.01	ns
$T_{DSPDCK\_OPMODE\_OPMODEREG}$/ $T_{DSPCKD\_OPMODE\_OPMODEREG}$	OPMODE input to OPMODE register CLK for XC devices	N/A	N/A	N/A	0.18/ 0.12	0.21/ 0.12	0.21/ 0.12	0.40/ 0.12	ns
	OPMODE input to OPMODE register CLK for XA and XQ devices				0.18/ 0.16	N/A	0.21/ 0.22	0.40/ 0.12	
Setup and Hold Times of Data Pins to the Pipeline Register Clock									
$T_{DSPDCK\_A\_MREG}$/ $T_{DSPCKD\_A\_MREG}$	A input to M register CLK	N/A	Yes	N/A	3.06/ –0.40	3.51/ –0.40	3.51/ –0.40	3.97/ –0.40	ns
$T_{DSPDCK\_B\_MREG}$/ $T_{DSPCKD\_B\_MREG}$	B input to M register CLK	Yes	Yes	N/A	3.96/ –0.68	4.58/ –0.68	4.58/ –0.68	7.00/ –0.68	ns
$T_{DSPDCK\_D\_MREG}$/ $T_{DSPCKD\_D\_MREG}$	D input to M register CLK	Yes	Yes	N/A	4.23/ –0.56	4.80/ –0.56	4.80/ –0.56	6.84/ –0.56	ns
$T_{DSPDCK\_OPMODE\_MREG}$/ $T_{DSPCKD\_OPMODE\_MREG}$	OPMODE to M register CLK	Yes	Yes	N/A	4.18/ –0.48	4.80/ –0.48	4.80/ –0.48	6.88/ –0.48	ns
		No	Yes	N/A	2.37/ –0.48	2.70/ –0.48	2.70/ –0.48	4.28/ –0.48	ns
Setup and Hold Times of Data/Control Pins to the Output Register Clock									
$T_{DSPDCK\_A\_PREG}$/ $T_{DSPCKD\_A\_PREG}$	A input to P register CLK	N/A	Yes	Yes	4.32/ –0.76	5.06/ –0.76	5.06/ –0.76	7.52/ –0.76	ns
$T_{DSPDCK\_B\_PREG}$/ $T_{DSPCKD\_B\_PREG}$	B input to P register CLK	Yes	Yes	Yes	5.87/ –0.59	6.87/ –0.59	6.87/ –0.59	10.55/ –0.59	ns
		No	Yes	Yes	4.14/ –0.93	4.68/ –0.93	4.68/ –0.93	8.12/ –0.93	ns
$T_{DSPDCK\_C\_PREG}$/ $T_{DSPCKD\_C\_PREG}$	C input to P register CLK	N/A	N/A	Yes	2.20/ –0.23	2.25/ –0.23	2.25/ –0.23	3.27/ –0.23	ns
$T_{DSPDCK\_D\_PREG}$/ $T_{DSPCKD\_D\_PREG}$	D input to P register CLK	Yes	Yes	Yes	5.90/ –0.92	6.91/ –0.92	6.91/ –0.92	10.39/ –0.92	ns

Table 54: **Switching Characteristics for the Delay-Locked Loop (DLL)[1] *(Cont'd)***

Symbol	Description	Speed Grade								Units
		-3		-3N		-2		-1L		
		Min	Max	Min	Max	Min	Max	Min	Max	
LOCK_DLL[3]	When using the DLL alone: The time from deassertion at the DCM's reset input to the rising transition at its LOCKED output. When the DCM is locked, the CLKIN and CLKFB signals are in phase. CLKIN_FREQ_DLL < 50 MHz.	–	5	–	5	–	5	–	5	ms
	When using the DLL alone: The time from deassertion at the DCM's reset input to the rising transition at its LOCKED output. When the DCM is locked, the CLKIN and CLKFB signals are in phase. CLKIN_FREQ_DLL > 50 MHz	–	0.60	–	0.60	–	0.60	–	0.60	ms
Delay Lines										
DCM_DELAY_STEP[5]	Finest delay resolution, averaged over all steps.	10	40	10	40	10	40	10	40	ps

Notes:
1. The values in this table are based on the operating conditions described in Table 2 and Table 53.
2. Indicates the maximum amount of output jitter that the DCM adds to the jitter on the CLKIN input.
3. For optimal jitter tolerance and faster LOCK time, use the CLKIN_PERIOD attribute.
4. Some jitter and duty-cycle specifications include 1% of input clock period or 0.01 UI. For example, this data sheet specifies a maximum jitter of ±(1% of CLKIN period + 150 ps). Assuming that the CLKIN frequency is 100 MHz, the equivalent CLKIN period is 10 ns. Since 1% of 10 ns is 0.1 ns or 100 ps, the maximum jitter is ±(100 ps + 150 ps) = ±250 ps.
5. A typical delay step size is 23 ps.
6. The timing analysis tools use the CLK_FEEDBACK = 1X condition for the CLKIN_CLKFB_PHASE value (reported as phase error). When using CLK_FEEDBACK = 2X, add 100 ps to the phase error for the CLKIN_CLKFB_PHASE value (as shown in this table).

Table 55: **Recommended Operating Conditions for the Digital Frequency Synthesizer (DFS)[1]**

Symbol	Description	Speed Grade								Units
		-3		-3N		-2		-1L		
		Min	Max	Min	Max	Min	Max	Min	Max	
Input Frequency Ranges[2]										
CLKIN_FREQ_FX	Frequency for the CLKIN input. Also described as F_{CLKIN}.	0.5	375[3]	0.5	375[3]	0.5	333[3]	0.5	200[3]	MHz
Input Clock Jitter Tolerance[4]										
CLKIN_CYC_JITT_FX_LF	Cycle-to-cycle jitter at the CLKIN input, based on CLKFX output frequency: FCLKFX < 150 MHz.	–	±300	–	±300	–	±300	–	±300	ps
CLKIN_CYC_JITT_FX_HF	Cycle-to-cycle jitter at the CLKIN input, based on CLKFX output frequency: FCLKFX > 150 MHz.	–	±150	–	±150	–	±150	–	±150	ps
CLKIN_PER_JITT_FX	Period jitter at the CLKIN input.	–	±1	–	±1	–	±1	–	±1	ns

Notes:
1. DFS specifications apply when using either of the DFS outputs (CLKFX or CLKFX180).
2. When using both DFS and DLL outputs on the same DCM, follow the more restrictive CLKIN_FREQ_DLL specifications in Table 53.
3. The CLKIN_DIVIDE_BY_2 attribute increases the effective input frequency range. When set to TRUE, the input clock frequency is divided by two as it enters the DCM. Input clock frequencies for the clock buffer being used can be increased up to the F_{MAX} (see Table 48 and Table 49 for BUFG and BUFIO2 limits).
4. CLKIN input jitter beyond these limits can cause the DCM to lose LOCK.

Table 73: **Global Clock Setup and Hold With DCM in Source-Synchronous Mode**

Symbol	Description	Device	Speed Grade				Units
			-3	-3N	-2	-1L	
Input Setup and Hold Time Relative to Global Clock Input Signal for LVCMOS25 Standard.(1)							
T_{PSDCM0}/ T_{PHDCM0}	No Delay Global Clock and IFF(2) with DCM in Source-Synchronous Mode	XC6SLX4	0.71/0.65	N/A	0.72/1.22	1.58/1.18	ns
		XC6SLX9	0.71/0.69	0.71/1.19	0.72/1.36	1.58/1.18	ns
		XC6SLX16	0.86/0.52	0.92/0.57	1.04/0.60	1.02/1.06	ns
		XC6SLX25	0.84/0.58	0.90/0.59	1.01/0.59	1.58/1.07	ns
		XC6SLX25T	0.84/0.58	0.90/0.59	1.01/0.59	N/A	ns
		XC6SLX45	0.85/0.70	0.90/0.76	0.98/0.79	1.34/1.34	ns
		XC6SLX45T	0.85/0.70	0.90/0.76	0.98/0.79	N/A	ns
		XC6SLX75	1.00/0.62	1.06/0.63	1.15/0.63	1.65/1.46	ns
		XC6SLX75T	1.00/0.71	1.06/0.72	1.15/0.72	N/A	ns
		XC6SLX100	0.81/0.68	0.81/0.69	0.94/0.69	1.42/2.07	ns
		XC6SLX100T	0.81/0.68	0.81/0.69	0.94/0.69	N/A	ns
		XC6SLX150	0.68/0.98	0.69/0.99	0.79/0.99	1.45/1.60	ns
		XC6SLX150T	0.68/0.98	0.69/0.99	0.79/0.99	N/A	ns
		XA6SLX4	0.81/0.74	N/A	0.72/1.36	N/A	ns
		XA6SLX9	0.81/0.74	N/A	0.72/1.36	N/A	ns
		XA6SLX16	1.01/0.56	N/A	1.04/0.60	N/A	ns
		XA6SLX25	0.94/0.76	N/A	1.06/0.77	N/A	ns
		XA6SLX25T	0.94/0.76	N/A	1.14/0.77	N/A	ns
		XA6SLX45	0.86/0.74	N/A	0.98/0.78	N/A	ns
		XA6SLX45T	0.86/0.74	N/A	0.98/0.78	N/A	ns
		XA6SLX75	1.02/0.71	N/A	1.15/0.72	N/A	ns
		XA6SLX75T	1.02/0.71	N/A	1.15/0.72	N/A	ns
		XA6SLX100	N/A	N/A	1.37/0.75	N/A	ns
		XQ6SLX75	N/A	N/A	1.15/0.72	1.65/1.46	ns
		XQ6SLX75T	1.02/0.71	N/A	1.15/0.72	N/A	ns
		XQ6SLX150	N/A	N/A	0.79/1.15	1.45/1.60	ns
		XQ6SLX150T	0.73/1.15	N/A	0.79/1.15	N/A	ns

Notes:
1. Setup and Hold times are measured over worst case conditions (process, voltage, temperature). Setup time is measured relative to the Global Clock input signal using the slowest process, highest temperature, and lowest voltage. Hold time is measured relative to the Global Clock input signal using the fastest process, lowest temperature, and highest voltage. These measurements include DCM CLK0 jitter.
2. IFF = Input Flip-Flop or Latch
3. Use IBIS to determine any duty-cycle distortion incurred using various standards.

Source-Synchronous Switching Characteristics

The parameters in this section provide the necessary values for calculating timing budgets for Spartan-6 FPGA source-synchronous transmitter and receiver data-valid windows.

Table 78: **Duty Cycle Distortion and Clock-Tree Skew**

Symbol	Description	Device[1]	Speed Grade				Units
			-3	-3N	-2	-1L	
T_{DCD_CLK}	Global Clock Tree Duty Cycle Distortion[2]	LX4	0.20	N/A	0.20	0.35	ns
		LX9	0.20	0.20	0.20	0.35	ns
		LX16	0.20	0.20	0.20	0.35	ns
		LX25	0.20	0.20	0.20	0.35	ns
		LX25T	0.20	0.20	0.20	N/A	ns
		LX45	0.20	0.20	0.20	0.35	ns
		LX45T	0.20	0.20	0.20	N/A	ns
		LX75	0.20	0.20	0.20	0.35	ns
		LX75T	0.20	0.20	0.20	N/A	ns
		LX100	0.20	0.20	0.20	0.35	ns
		LX100T	0.20	0.20	0.20	N/A	ns
		LX150	0.35	0.35	0.35	0.35	ns
		LX150T	0.35	0.35	0.35	N/A	ns
T_{CKSKEW}	Global Clock Tree Skew[3]	LX4	0.25	N/A	0.25	0.29	ns
		LX9	0.25	0.25	0.25	0.29	ns
		LX16	0.15	0.15	0.15	0.22	ns
		LX25	0.26	0.26	0.26	0.41	ns
		LX25T	0.26	0.26	0.26	N/A	ns
		LX45	0.20	0.20	0.20	0.28	ns
		LX45T	0.20	0.20	0.20	N/A	ns
		LX75	0.56	0.56	0.56	0.50	ns
		LX75T	0.56	0.56	0.56	N/A	ns
		XC6SLX100[4]	0.22	0.22	0.22	0.21	ns
		XA6SLX100[4]	N/A	N/A	0.43	N/A	ns
		LX100T	0.22	0.22	0.22	N/A	ns
		LX150	0.48	0.48	0.48	0.35	ns
		LX150T	0.48	0.48	0.48	N/A	ns
T_{DCD_BUFIO2}	I/O clock tree duty cycle distortion	LX devices	0.25	0.25	0.25	0.50	ns
		LXT devices	0.25	0.25	0.25	N/A	ns

Table 81: **Source-Synchronous Pin-to-Pin Setup/Hold and Clock-to-Out Using BUFIO2**

Symbol	Description	Device	Speed Grade				Units
			-3	-3N	-2	-1L	
Data Input Setup and Hold Times Relative to a Forwarded Clock Input Pin Using BUFIO2							
T_{PSCS}/T_{PHCS}	IFF setup/hold using BUFIO2 clock	XC6SLX4	0.57/0.94	N/A	0.95/1.12	0.27/1.56	ns
		XC6SLX9	0.40/0.95	0.50/0.96	0.60/1.12	0.27/1.56	ns
		XC6SLX16	0.48/0.74	0.55/0.75	0.69/0.83	1.27/1.31	ns
		XC6SLX25	0.28/1.02	0.28/1.12	0.28/1.24	0.15/1.78	ns
		XC6SLX25T	0.28/1.02	0.28/1.12	0.28/1.24	N/A	ns
		XC6SLX45	0.42/1.19	0.44/1.29	0.50/1.40	0.12/1.83	ns
		XC6SLX45T	0.42/1.19	0.44/1.29	0.50/1.40	N/A	ns
		XC6SLX75	0.38/1.48	0.38/1.63	0.38/1.84	0.05/2.78	ns
		XC6SLX75T	0.38/1.48	0.38/1.63	0.38/1.84	N/A	ns
		XC6SLX100	0.06/1.48	0.06/1.63	0.06/1.87	–0.03/2.72	ns
		XC6SLX100T	0.06/1.48	0.06/1.63	0.06/1.87	N/A	ns
		XC6SLX150	0.04/1.73	0.04/1.75	0.04/1.98	–0.08/3.07	ns
		XC6SLX150T	0.04/1.73	0.04/1.75	0.04/1.98	N/A	ns
		XA6SLX4	0.64/0.96	N/A	0.97/1.12	N/A	ns
		XA6SLX9	0.44/0.99	N/A	0.62/1.16	N/A	ns
		XA6SLX16	0.50/0.78	N/A	0.69/0.83	N/A	ns
		XA6SLX25	0.28/1.04	N/A	0.28/1.25	N/A	ns
		XA6SLX25T	0.28/1.04	N/A	0.28/1.25	N/A	ns
		XA6SLX45	0.43/1.21	N/A	0.50/1.40	N/A	ns
		XA6SLX45T	0.43/1.21	N/A	0.50/1.40	N/A	ns
		XA6SLX75	0.38/1.49	N/A	0.38/1.84	N/A	ns
		XA6SLX75T	0.38/1.49	N/A	0.38/1.84	N/A	ns
		XA6SLX100	N/A	N/A	1.01/1.63	N/A	ns
		XQ6SLX75	N/A	N/A	0.38/1.84	0.05/2.78	ns
		XQ6SLX75T	0.38/1.49	N/A	0.38/1.84	N/A	ns
		XQ6SLX150	N/A	N/A	0.04/1.98	–0.08/3.07	ns
		XQ6SLX150T	0.04/1.75	N/A	0.04/1.98	N/A	ns

Table 81: **Source-Synchronous Pin-to-Pin Setup/Hold and Clock-to-Out Using BUFIO2 *(Cont'd)***

Symbol	Description	Device	Speed Grade				Units
			-3	-3N	-2	-1L	
Pin-to-Pin Clock-to-Out Using BUFIO2							
$T_{ICKOFCS}$	OFF clock-to-out using BUFIO2 clock	XC6SLX4	5.51	N/A	6.95	8.45	ns
		XC6SLX9	5.51	5.89	6.95	8.45	ns
		XC6SLX16	5.31	5.70	6.67	8.21	ns
		XC6SLX25	5.53	6.00	7.02	8.72	ns
		XC6SLX25T	5.53	6.00	7.02	N/A	ns
		XC6SLX45	5.76	6.18	7.22	8.77	ns
		XC6SLX45T	5.76	6.18	7.22	N/A	ns
		XC6SLX75	5.94	6.46	7.57	9.72	ns
		XC6SLX75T	5.94	6.46	7.57	N/A	ns
		XC6SLX100	6.09	6.53	7.60	9.66	ns
		XC6SLX100T	6.09	6.53	7.60	N/A	ns
		XC6SLX150	6.29	6.69	7.81	9.94	ns
		XC6SLX150T	6.29	6.69	7.81	N/A	ns
		XA6SLX4	5.83	N/A	6.95	N/A	ns
		XA6SLX9	5.83	N/A	6.95	N/A	ns
		XA6SLX16	5.65	N/A	6.68	N/A	ns
		XA6SLX25	5.85	N/A	7.03	N/A	ns
		XA6SLX25T	5.85	N/A	7.03	N/A	ns
		XA6SLX45	6.07	N/A	7.25	N/A	ns
		XA6SLX45T	6.07	N/A	7.25	N/A	ns
		XA6SLX75	6.26	N/A	7.57	N/A	ns
		XA6SLX75T	6.26	N/A	7.57	N/A	ns
		XA6SLX100	N/A	N/A	7.48	N/A	ns
		XQ6SLX75	N/A	N/A	7.57	9.72	ns
		XQ6SLX75T	6.26	N/A	7.57	N/A	ns
		XQ6SLX150	N/A	N/A	7.81	9.94	ns
		XQ6SLX150T	6.62	N/A	7.81	N/A	ns

Date	Version	Description of Revisions
06/14/10	1.5	In Table 2, added note 5 and added temperature range to V_{FS} and R_{FUSE}. Removed speed grade delineation, revised I_{RPD} description, and updated note 2 in Table 4. Added note 2 to Table 7. Added DIFF_MOBILE_DDR to Table 8 and Table 10. Added note 4 to Table 15. Changed minimum DV_{PPIN} in Table 16. Updated $F_{GTPDRPCLK}$ in Table 19. Increased maximum T_{LLSKEW} in Table 22. Updated descriptions and added data to Table 23. Removed note 1 and added new data to the Networking Applications section in Table 25. Updated Table 26 and Table 27 to the data in ISE v12.1 software with speed specification v1.08. In Table 28, added DIFF_MOBILE_DDR and updated -4 speed grade data. Updated the maximum I/O pairs per bank in Table 33. Updated note 2 on Table 39. Revised the F_{MAX} in Table 44. In Table 47, updated description for $T_{SMCKCSO}$, revised values for T_{POR} and added Min value, added $T_{BPIICCK}$ and $T_{SPIICCK}$. Also in Table 47, added device dependencies to F_{SMCCK} and F_{RBCCK}. Updated and added data to Table 63 through Table 78, and Table 81. In Table 79, added data on the XC6SLX45-FG(G)676 and revised the XC6SLX45T and XC6SLX150T values. The following changes to this specification are addressed in the product change notice XCN10024, *MCB Performance and JTAG Revision Code for Spartan-6 LX16 and LX45 FPGAs*. In Table 2, revised the V_{CCINT} to add the memory controller block extended performance specifications. In Table 25, changed the standard specifications and added extended performance specifications for the memory controller block and note 2. Added note 4 and updated values in Table 34.
06/24/10	1.6	Production release of XC6SLX45T (-2 and -3 speed grades), XC6SLX16 and XC6SLX45 (-3 speed grade) devices which includes changes to Table 26 and Table 27 (ISE v12.1 software with speed specification v1.08). Added the -3N speed grade, which designates Spartan-6 devices that do not support MCB functionality. This includes changes to Table 2 (note 2), Table 25 (note 4), and Switching Characteristics (Table 26). Updated Simultaneously Switching Outputs discussion. Added -3 speed grade values for T_{TAP} and F_{MINCAL} values in Table 39. In Table 40, updated T_{RPW} (-2 and -3 speed grade) values and F_{TOG} (-3 speed grade) values. In Table 48, updated T_{GIO} (-2 and -3 speed grade) values. Updated -3 values in spread spectrum section of Table 57.
07/16/10	1.7	Production release of specific devices listed in Table 26 and Table 27 using ISE v12.2 software with speed specification v1.11. Added note 4 advising designers of the patch which contains v1.11. Also updated the -1L speed specification to v1.04. Updated numerous -4 and -1L values. Added -4 T_{TAP} values and F_{MINCAL} to Table 39. Revised T_{CINCK}/T_{CKCIN} in Table 40. In Table 41, revised T_{SHCKO}. In Table 42, revised T_{REG}. Added new -1L values to Table 47. Added and updated values in Table 79.
07/26/10	1.8	Production release of XC6SLX25, XC6SLX25T, XC6SLX100 and XC6SLX100T in the specific speed grades listed in Table 26 and Table 27 using ISE v12.2 software with speed specification v1.11. Added note 7 to Table 2 and moved V_{FS} and R_{FUSE} to a new Table 3. Added I_{HS} and note 4 to Table 4. Added note 1 to Table 28. Added and updated SSO limits per V_{CCO}/GND pairs in Table 34. Added note 3 to Table 47. In Table 54, removed -1L specifications for CLKOUT_PER_JITT_DV1/2 and revised CLKIN_CLKFB_PHASE and CLKOUT_PHASE_DLL values. Updated note 3 in both Table 56 and Table 57.
08/23/10	1.9	Updated values for $F_{GTPRANGE1}$, $F_{GTPRANGE2}$, and $F_{GPLLMIN}$ in Table 18. Revised -3 and -4 values in Table 21. Removed the -1L speed grade readback support restriction and note 3 in Table 47.
11/05/10	1.10	Production release of XC6SLX4 and XC6SLX9 in the specific speed grades listed in Table 26 and Table 27 using ISE v12.3 software with speed specification v1.12 for the -2 speed grade available in the 12.3 *Speed Files Patch*. Added note 3 advising designers of the patch which contains v1.12. In Table 2, added note 4. In Table 4, added note 2. In Table 10, added notes 2 and 3. In Table 44, added note 2. In Table 47, updated symbol for T_{SMWCCK}/T_{SMCCKW}, changed -1L values for $T_{USERCCLKH}$ and $T_{USERCCLKL}$, and added and revised the modes for F_{MCCK} and F_{SMCCK}. In Table 53, redefined and expanded description for CLKIN_FREQ_DLL and rewrote note 3. Updated title of Table 58. Also in Table 78, revised T_{DCD_CLK} for XC6SLX150 and XC6SLX150T. Changed description of T_{PSFD}/ T_{PHFD} in Table 71. For the -1L speed grade, updated data sheet to ISE 12.3 software with speed specification v1.05 which revised the values in the following tables: Table 25, Table 28, Table 35, Table 36, Table 37, Table 40 through Table 43, Table 48 through Table 56, Table 62 through Table 78, Table 80, and Table 81. Updated Notice of Disclaimer.

Date	Version	Description of Revisions
01/10/11	1.11	Production release of XC6SLX4 and XC6SLX9 in the specific speed grades listed in Table 26 and Table 27 using ISE v12.4 software with speed specification v1.15 for the -4, -3, -3N, and -2 speed grades. Added note 3 to Table 27. Also updated the -1L speed grade requirements to ISE v12.4 software with speed specification v1.06. Revised -3N definition throughout the document. Added note 4 to Table 2 and updated note 5. Added information on V_{CCINT} to note 1 in Table 5. Updated Networking Applications -3 values in Table 25 to match improvements made in ISE v12.4. In Table 28, added note 1 and revised the T_{IOTP} values for LVDS_33, LVDS_25, MINI_LVDS_33, MINI_LVDS_25, RSDS_33, RSDS_25, TMDS_33. PPDS_33, and PPDS_25. Added note 3 to Table 55.
02/11/11	1.12	As described in XCN11008: *Product Discontinuation Notice For Spartan-6 LXT -4 Devices*, the -4 speed specifications have been discontinued. As outlined in page 2 of the XCN, designers currently using -4 speed specifications should rerun timing analysis using the new -3 speed specifications before moving to a replacement device. Updated the networking applications section of Table 25. Updated -2 speed specifications throughout document and added note 3 to Table 27 advising designers to use the -2 speed specification update (v1.17) with the ISE 12.4 software patch. Added F_{CLKDIV} to Table 37 and Table 38. Updated note 2 in Table 39. Updated units for $T_{SMCKCSO}$ and T_{BPICCO} in Table 47. Updated -1L in Table 71. Removed Note 2: *Package delay information is available for these device/package combinations. This information can be used to deskew the package* from Table 79.
03/31/11	2.0	Production release of XC6SLX45 in the -1L speed grades listed in Table 26 and Table 27 using ISE v13.1 software with -1L speed specification v1.06. In Table 39, removed values in the -1L column and added note 3 as IODELAY2 only supports Tap0 for lower-power devices. Updated copyright page 1 and Notice of Disclaimer.
05/20/11	2.1	Production release of XC6SLX100 and XC6SLX150 in the specific speed grades listed in Table 26 and Table 27 using ISE v13.1 software with -1L speed specification v1.06. Updated Table 27 and Note 7 with changes per XCN11012: *Speed File Change for -3N Devices*. Revised Switching Characteristics section for speed specifications: v1.18 for -3, -3N, and -2; including improvements in Table 73 through Table 77 and Table 81. Removed *Memory Controller Block* from the performance heading in Table 2 and revised Note 2. In Table 4, added Note 1 to C_{IN} and updated the description of R_{IN_TERM}. Updated Note 1 in Table 5. Updated Note 1 of Table 7. In Table 25, added and removed -1L specifications, increased the standard performance DDR3 specifications, removed the extended performance DDR3 row and updated Note 3 and Note 4. Clarified the introductory information for Table 28 and Table 30. In Table 32: Revised V_{MEAS} value for LVCMOS12; revised V_{REF} for LVDS_25, LVDS_33, BLVDS_25,MINI_LVDS_25, MINI_LVDS_33, RSDS_25, and RSDS_33; revised R_{REF} for BLVDS_25 and TMDS_33; and added Note 4 and Note 5. Updated Note 2 and Note 3 in Table 39. In Table 47, revised the values and description of T_{POR} including adding Note 3. Also in Table 47, augmented the description and added specifications for F_{RBCCK} and removed XC6SLX4 from F_{MCCK} (maximum frequency, parallel mode (Master SelectMAP/BPI). Added BUFGMUX to Table 48 title. Added Table 50. In Table 52, revised specifications for $T_{EXTFDVAR}$ and $F_{INJITTER}$. In Table 54 removed the 5 MHz < CLKIN_FREQ_DLL parameter in the LOCK_DLL description. In both Table 56 and Table 57, removed the 5 MHz < F_{CLKIN} parameter in the LOCK_FX description. In Table 58, updated description for PSCLK_FREQ and PSCLK_PULSE. Revised title and symbol of Table 70, added new speed specifications for -1L, and added Note 2. Added Table 71.
07/11/11	2.2	Added the Automotive XA Spartan-6 and Defense-grade Spartan-6Q devices to all appropriate tables while sometimes removing the XC6S nomenclature. Added expanded temperature range (Q) to all appropriate tables. Updated T_{SOL} packages in Table 1. Added R_{OUT_TERM} to Table 4. Updated Note 2 on Table 13. Production release of the XC6SLX4, XC6SLX9, XC6SLX16, XC6SLX25, XC6SLX75, XQ6SLX75, and XQ6SLX150 in Table 26 and Table 27 using ISE v13.2 software with -1L speed specification v1.07. Production release of the XA6SLX16, XA6SLX25T, XA6SLX45, XA6SLX45T, XQ6SLX75, XQ6SLX75T, XQ6SLX150, and XQ6SLX150T in Table 26 and Table 27 using ISE v13.2 software with -2 and -3 speed specification v1.19. Added Table 29: IOB Switching Characteristics for the Automotive XA Spartan-6 and the Spartan-6Q Devices(1). Updated CS(G)484 from CSG484 throughout data sheet. Clarified Note 3 in Table 39.
08/08/11	2.3	Production release of the XA6SLX25, XA6SLX75, and XA6SLX75T in Table 26 and Table 27 using ISE v13.2 software with -2 and -3 speed specification v1.19.